

Erratum: "Precision cutting of nanotubes with a low-energy electron beam" [Appl. Phys. Lett. 86, 053109 (2005)]

T. D. Yuzvinsky, A. M. Fennimore, W. Mickelson, C. Esquivias, and A. Zettl
*Department of Physics, University of California at Berkeley, and Materials Sciences Division, Lawrence
Berkeley National Laboratory, Berkeley, California 94720*

(Received 8 June 2005; accepted 23 June 2005; published online 3 August 2005)

[DOI: 10.1063/1.2000345]

The scale bars in Fig. 1 were incorrectly labeled and were not 20 nm. The correct scale bars and labels are shown below. Thus, the width of the cut in Fig. 1(d) is approximately 25 nm, not 40 nm as was reported in the text. Hence, the cutting process is actually more precise than originally reported. No other conclusions of the paper are affected.

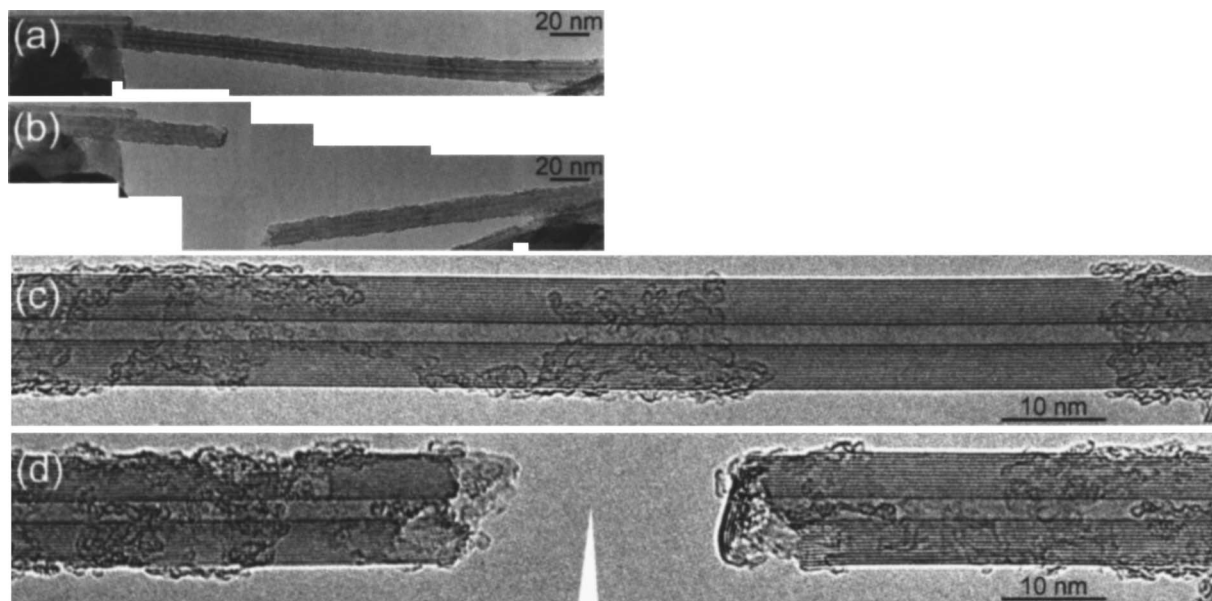


FIG. 1. Composite TEM micrographs of (a) a nanotube in its pristine state suspended on a TEM grid, (b) the same nanotube after cutting, (c) a close-up image of the same nanotube, and (d) the cut segments of the nanotube, rotated and aligned to vertically correspond with the same sections in (c).